

Characterization of Materials

EXAM 3 will cover:

- 1) **X-ray generation:** How x-rays are produced, role of energy levels of electrons in atoms (Bohr model), equations in C ch 1, various spectra, labels of x-rays ($K\alpha$, etc.) and emitted electrons, relation of this info regarding interactions of electrons or photons with atoms in the characterization techniques that we have discussed.
- 2) **Absorption:** Equations, mechanisms of absorption, graphs, problem-solving.
- 3) **Diffraction:** Bragg's law, peak broadening, equations.
- 4) **Intensity** of XRD peaks, factors in the I_{INT} equation, effects of these factors in I_{INT} on intensity of specific (hkl) lines in 2θ , especially form factor and the Structure Factor and their importance. Know how to solve for F_{hkl} .
- 5) **Counters** (general characteristics)
- 6) **Surface spectroscopies** Electron spectroscopies: XPS, AES; Ion spectroscopies: ISS, MEIS (not much detail, only its source energy levels), RBS, SIMS. Know mechanisms and information that can be obtained. Depth of analysis, lateral resolution.
- 7) **Electron microscopies:** Limit of resolution, SEM vs TEM, use of fluorescence attachments and WDS (and EDS, but we covered WDS in more detail in section on fluorescence spectroscopy), info that can be obtained. HAADF-STEM, EELS (Similarity of EELS to spectroscopies and use of Bohr model).
- 8) **Scanning probe microscopies:** STM, AFM, mechanisms of each, benefits, resolution, etc.
- 9) **Vibrational Spectroscopies:** IR and Raman spectroscopies

IN GENERAL:

1. Know 'particles in' and 'particles out' for each technique (and the underlying similarities of a particle in creating several particles out).
2. Know which technique uses the specific 'particles out' for analysis.
3. For all techniques, know info gained, depth probed, lateral resolution, bulk or surface usage (Table of Techniques).
4. Know strengths of each technique (why use one vs another - for example, SEM vs TEM, or XPS vs AES, etc.).
5. Remember what **figures of output data** look like for specific techniques; **use labels of the axes** as an aid. The additional reading on the website can help with figures if you don't recall those in class.
6. Know **why** one would use multiple techniques to investigate a material problem.

Which technique do you use if you need (with some possible answers):

to determine elements present in sample; (XRF)

good lateral resolution to determine elements present in a surface; (AES)

the microstructure; (SEM)

the structure around specific species in a sample; (EXAFS)

the phases present; (XRD)

the chemistry of the surface-(chemistry means both elements and bonding); (XPS)

the chemistry of a material (IR/Raman)

etc.

Of course, anything discussed in class should be understood; you can clarify if necessary reading the chapters in Cullity, and Brundel reading on website and the added reading that is for those who want additional clarification or more in-depth info. The homework and answers covered in class will help.